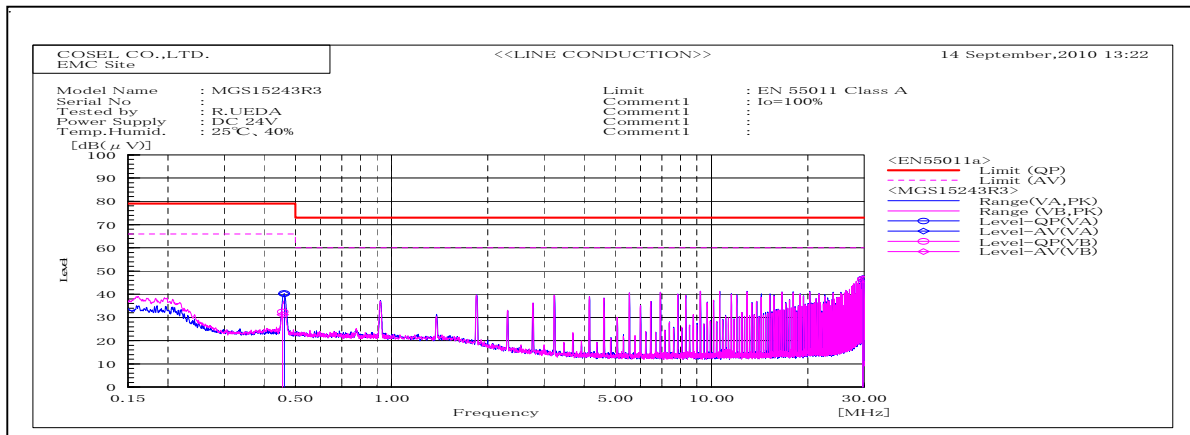
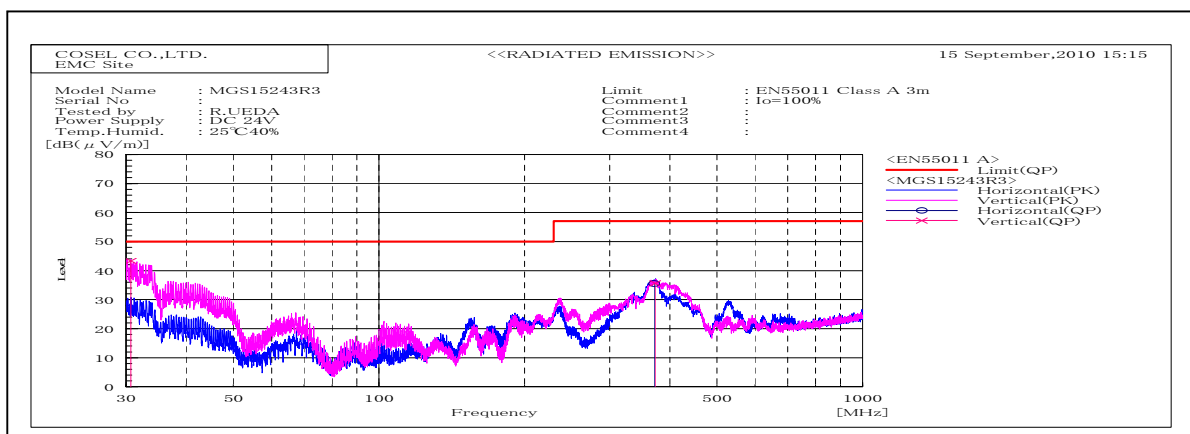


DATA SHEET		Date	21-Sep-10
Model	MGS15243R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45736		VB	22.4	21.2	10	32.4	31.2	79	66	46.6	34.8	Pass	
0.46144		VA	30.2	30	10.1	40.3	40.1	79	66	38.7	25.9	Pass	
29.72695		VB	35.3	35.6	11	46.3	46.6	73	60	26.7	13.4	Pass	
29.728		VA	35.9	36.1	10.6	46.5	46.7	73	60	26.5	13.3	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
30.679	V	Stable	57.1	-13.8		43.3		50	6.7	Pass	101	28	
371.043	H	Stable	51.2	-15.6		35.6		57	21.4	Pass	101	157	
372.492	V	Stable	51.1	-15.5		35.6		57	21.4	Pass	104	82	

# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission



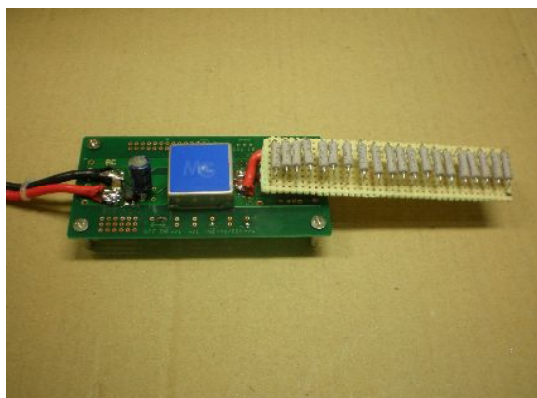


## Conditions

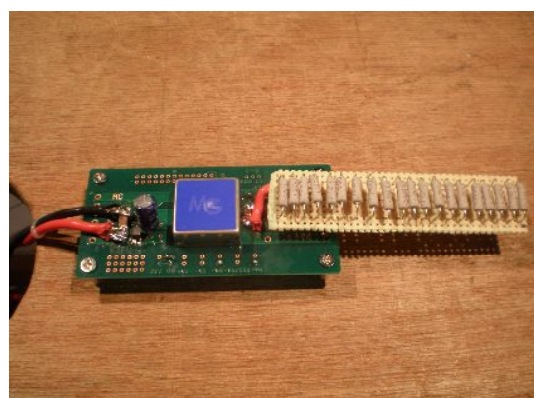
Test : EMI  
Model Name : MGS1524□□/MGW1524□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

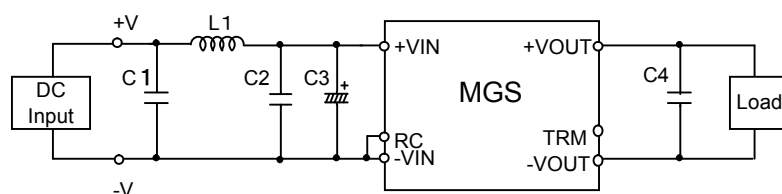


Fig.1 Testing circuitry 1

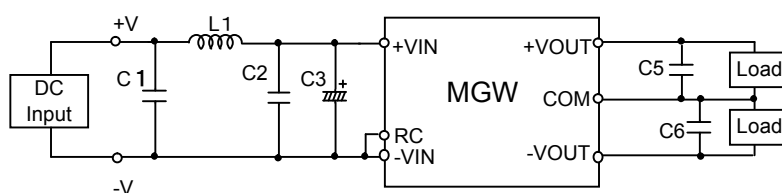


Fig.2 Testing circuitry 2

L1	:	2.2 $\mu$ H	CI4C-2R2	(KORIN ELECTRONICS)
C1,C2	:	50V 6.8 $\mu$ F	C4532X7R1H685MT	(TDK)
C3	:	50V 100 $\mu$ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 $\mu$ F	CM32X5R226K25A	(KYOCERA)